


<b>Search Notes</b>  	<b>Application/Control No.</b>  10596456	<b>Applicant(s)/Patent Under Reexamination</b>  REDERT ET AL.
	<b>Examiner</b>  Phu K Nguyen	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner
345	419, 424, 427	6/18/09	pn
382	292, 293	6/18/09	pn
701	3	6/18/09	pn

SEARCH NOTES		
Search Notes	Date	Examiner
WEST search: perspective projection, scale, viewpoint	6/18/09	pn
INonPatent Literature: IEEE, ACM, Google	6/18/09	pn
Inventor Name search	6/18/09	pn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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